

PowerMOS transistor

BUK444-500B

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic full-pack envelope. The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

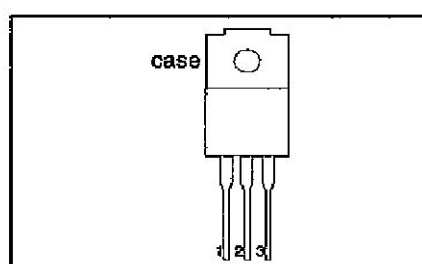
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V_{DS}	Drain-source voltage	500	V
I_D	Drain current (DC)	1.9	A
P_{tot}	Total power dissipation	25	W
$R_{DS(ON)}$	Drain-source on-state resistance	2.8	Ω

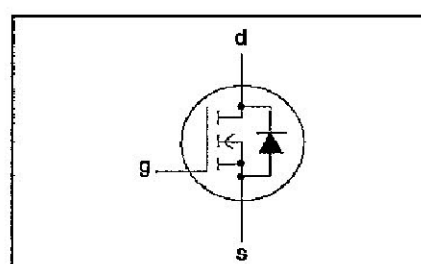
PINNING - SOT186

PIN	DESCRIPTION
1	gate
2	drain
3	source
case	isolated

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	Drain-source voltage	-	-	500	V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	500	V
$\pm V_{GS}$	Gate-source voltage	-	-	30	V
I_D	Drain current (DC)	$T_{hs} = 25^\circ\text{C}$	-	1.9	A
I_D	Drain current (DC)	$T_{hs} = 100^\circ\text{C}$	-	1.2	A
I_{DM}	Drain current (pulse peak value)	$T_{hs} = 25^\circ\text{C}$	-	7.6	A
P_{tot}	Total power dissipation	$T_{hs} = 25^\circ\text{C}$	-	25	W
T_{stg}	Storage temperature	-	-55	150	$^\circ\text{C}$
T_J	Junction Temperature	-	-	150	$^\circ\text{C}$

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th j-mb}$	Thermal resistance junction to mounting base	with heatsink compound	-	-	5	K/W
$R_{th j-a}$	Thermal resistance junction to ambient		-	55	-	K/W

PowerMOS transistor

BUK444-500B

STATIC CHARACTERISTICS

 $T_{\text{HS}} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{\text{GS}} = 0\text{ V}; I_{\text{D}} = 0.25\text{ mA}$	500	-	-	V
$V_{\text{GS}(\text{TO})}$	Gate threshold voltage	$V_{\text{DS}} = V_{\text{GS}}; I_{\text{D}} = 1\text{ mA}$	2.1	3.0	4.0	V
I_{DSS}	Zero gate voltage drain current	$V_{\text{DS}} = 500\text{ V}; V_{\text{GS}} = 0\text{ V}; T_{\text{J}} = 25\text{ }^{\circ}\text{C}$	-	2	20	μA
I_{DSS}	Zero gate voltage drain current	$V_{\text{DS}} = 500\text{ V}; V_{\text{GS}} = 0\text{ V}; T_{\text{J}} = 125\text{ }^{\circ}\text{C}$	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	$V_{\text{GS}} = \pm 30\text{ V}; V_{\text{DS}} = 0\text{ V}$	-	10	100	nA
$R_{\text{DS(ON)}}$	Drain-source on-state resistance	$V_{\text{GS}} = 10\text{ V}; I_{\text{D}} = 1.2\text{ A}$	-	2.4	2.8	Ω

DYNAMIC CHARACTERISTICS

 $T_{\text{HS}} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	$V_{\text{DS}} = 25\text{ V}; I_{\text{D}} = 1.2\text{ A}$	1.9	2.5	-	S
C_{iss}	Input capacitance	$V_{\text{GS}} = 0\text{ V}; V_{\text{DS}} = 25\text{ V}; f = 1\text{ MHz}$	-	400	500	pF
C_{oss}	Output capacitance		-	55	80	pF
C_{rss}	Feedback capacitance		-	20	55	pF
t_{don}	Turn-on delay time	$V_{\text{DD}} = 30\text{ V}; I_{\text{D}} = 2.3\text{ A};$	-	15	20	ns
t_{r}	Turn-on rise time	$V_{\text{GS}} = 10\text{ V}; R_{\text{GS}} = 50\text{ }\Omega;$	-	40	60	ns
t_{doff}	Turn-off delay time	$R_{\text{gen}} = 50\text{ }\Omega$	-	50	65	ns
t_{f}	Turn-off fall time		-	30	40	ns
L_{d}	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
L_{s}	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

ISOLATION

 $T_{\text{HS}} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{isol}	Repetitive peak voltage from all three terminals to external heatsink	R.H. $\leq 65\%$; clean and dustfree	-	-	1500	V
C_{isol}	Capacitance from T2 to external heatsink	$f = 1\text{ MHz}$	-	12	-	pF

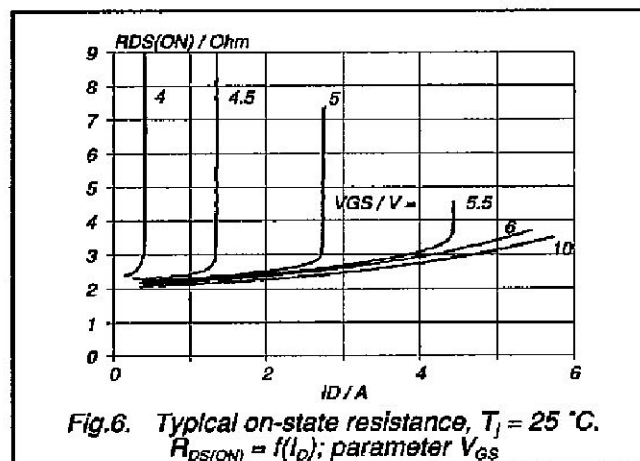
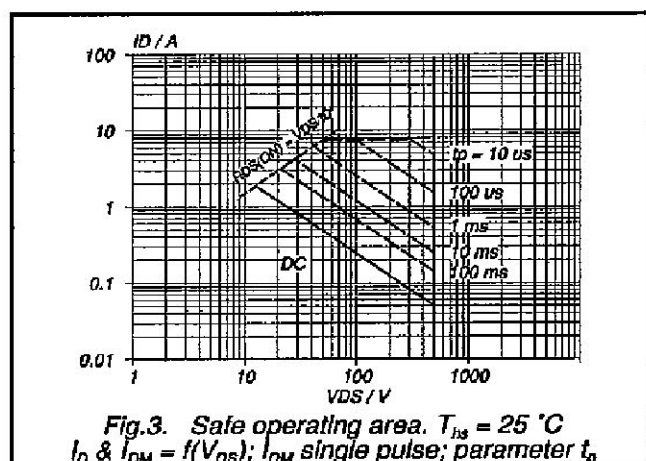
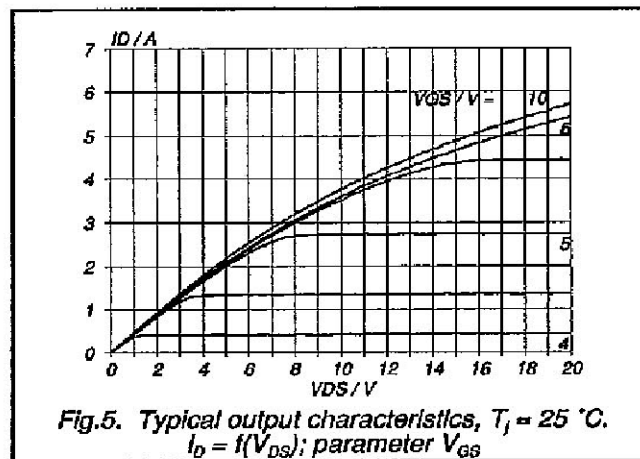
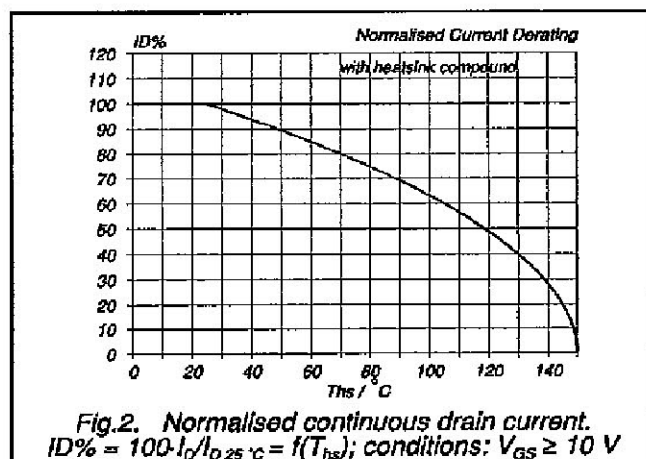
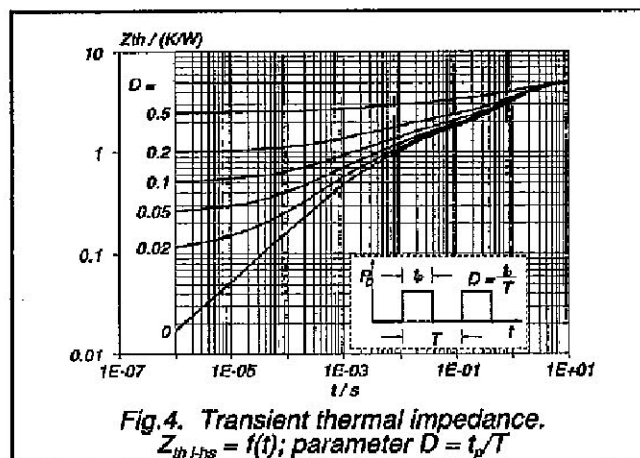
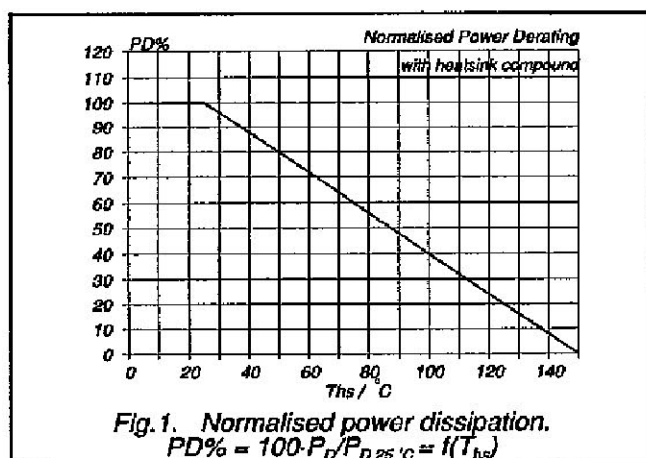
REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

 $T_{\text{HS}} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	2.1	A
I_{DRM}	Pulsed reverse drain current	-	-	-	8.4	A
V_{SD}	Diode forward voltage	$I_{\text{F}} = 2.1\text{ A}; V_{\text{GS}} = 0\text{ V}$	-	1.0	1.3	V
t_{r}	Reverse recovery time	$I_{\text{F}} = 2.1\text{ A}; -\text{d}I_{\text{F}}/\text{d}t = 100\text{ A}/\mu\text{s};$	-	270	-	ns
Q_{rr}	Reverse recovery charge	$V_{\text{GS}} = 0\text{ V}; V_{\text{R}} = 100\text{ V}$	-	2.0	-	μC

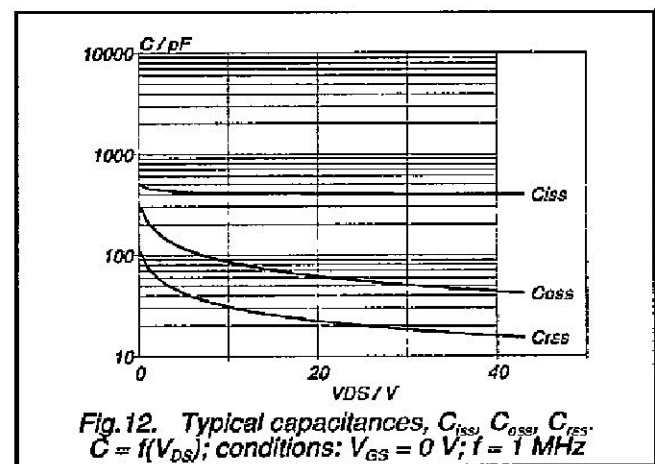
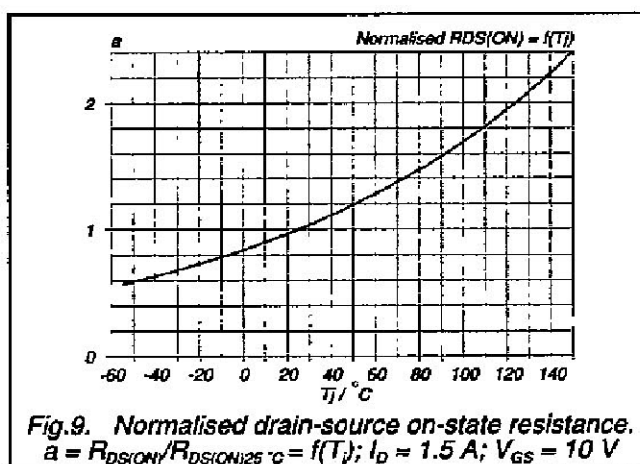
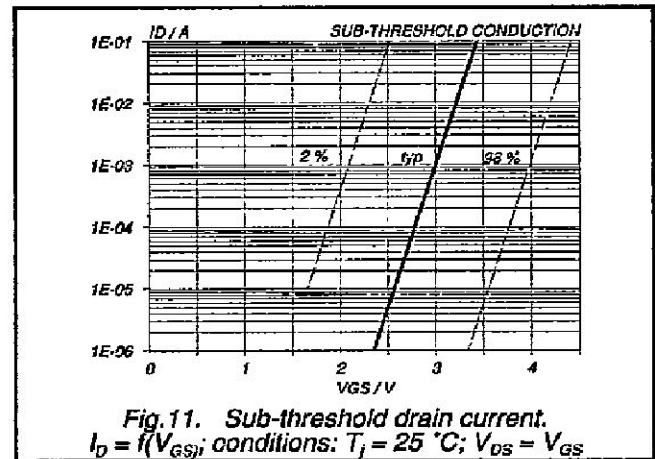
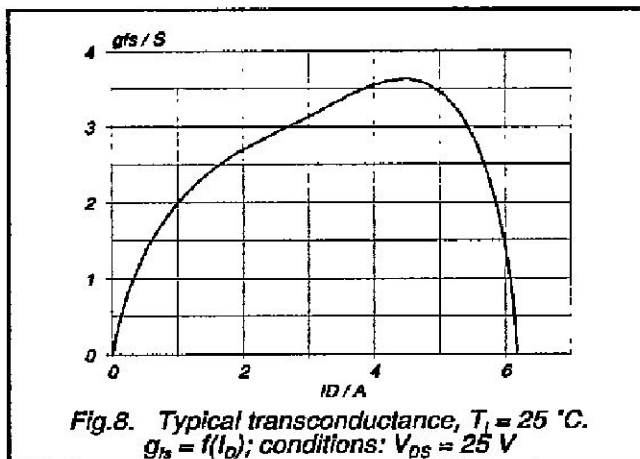
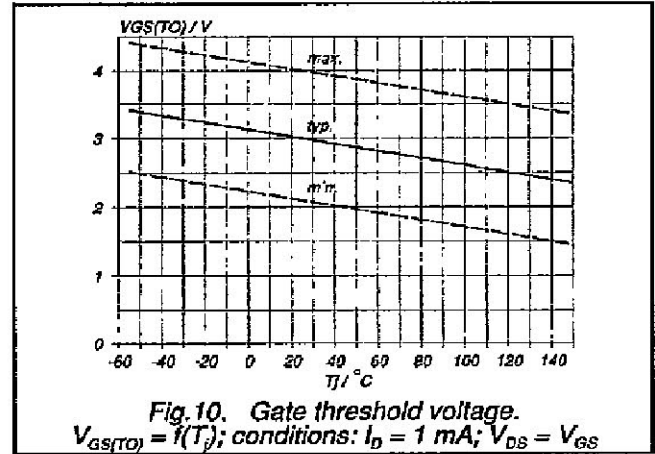
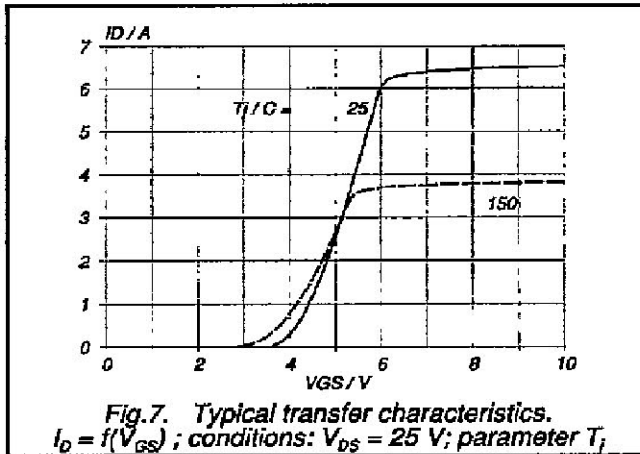
PowerMOS transistor

BUK444-500B



PowerMOS transistor

BUK444-500B



PowerMOS transistor

BUK444-500B

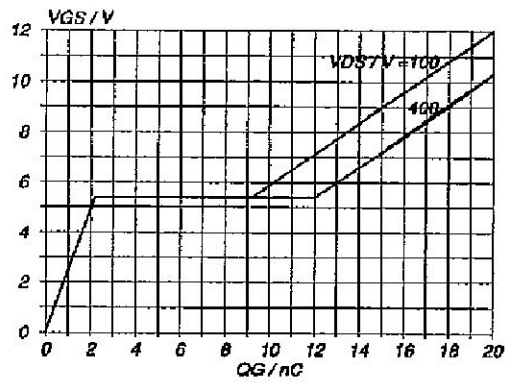


Fig. 13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; conditions: $I_D = 3.7$ A; parameter V_{DS}

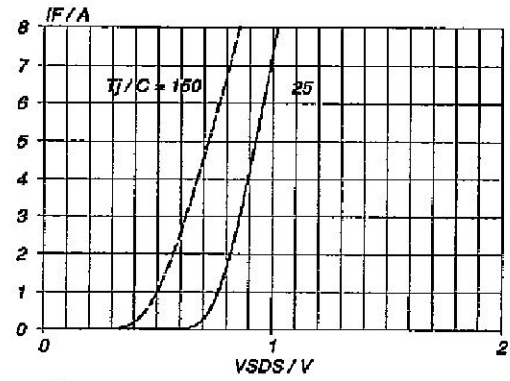


Fig. 14. Typical reverse diode current.
 $I_F = f(V_{SDS})$; conditions: $V_{GS} = 0$ V; parameter T_j